



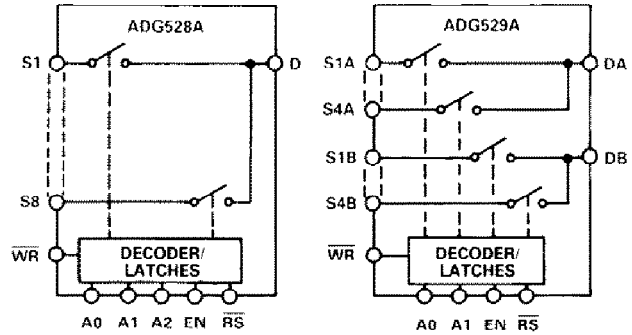
CMOS Latched 4/8 Channel Analog Multiplexers

ADG528A/ADG529A

FEATURES

- 44V Supply Maximum Rating
- V_{SS} to V_{DD} Analog Signal Range
- Single/Dual Supply Specifications
- Wide Supply Ranges (10.8V to 16.5V)
- Microprocessor Compatible (100ns \overline{WR} Pulse)
- Extended Plastic Temperature Range
(-40°C to +85°C)
- Low Leakage (20pA typ)
- Low Power Dissipation (28mW max)
- Available in 16-Lead DIP and
20-Lead LCCC/PLCC Packages
- Superior Alternative to:
DG528
DG529

FUNCTIONAL BLOCK DIAGRAMS



GENERAL DESCRIPTION

The ADG528A and ADG529A are CMOS monolithic analog multiplexers with 8 channels and dual 4 channels respectively. On-chip latches facilitate microprocessor interfacing. The ADG528A switches one of 8 inputs to a common output depending on the state of three binary addresses and an enable input. The ADG529A switches one of 4 differential inputs to a common differential output depending on the state of two binary addresses and an enable input. Both devices have TTL and 5V CMOS logic compatible digital inputs.

The ADG528A and ADG529A are designed on an enhanced LC²MOS process which gives an increased signal capability of V_{SS} to V_{DD} and enables operation over a wide range of supply voltages. The devices can comfortably operate anywhere in the 10.8V to 16.5V single or dual supply range. These multiplexers also feature high switching speeds and low R_{ON} .

PRODUCT HIGHLIGHTS

1. Single/Dual Supply Specifications with a Wide Tolerance:
The devices are specified in the 10.8V to 16.5V range for both single and dual supplies.
2. Easily Interfaced:
The ADG528A and ADG529A can be easily interfaced with microprocessors. The \overline{WR} signal latches the state of the address control lines and the enable line. The \overline{RS} signal clears both the address and enable data in the latches resulting in no output (all switches off). \overline{RS} can be tied to the microprocessor reset pin.

3. Extended Signal Range:
The enhanced LC²MOS processing results in a high breakdown and an increased analog signal range of V_{SS} to V_{DD} .
4. Break-Before-Make Switching:
Switches are guaranteed break-before-make so that input signals are protected against momentary shorting.
5. Low Leakage:
Leakage currents in the range of 20pA make these multiplexers suitable for high precision circuits.

ORDERING GUIDE

Model ¹	Temperature Range	Package Option ²
ADG528AKN	-40°C to +85°C	N-28
ADG528AKP	-40°C to +85°C	P-20A
ADG528ABQ	-40°C to +85°C	Q-18
ADG528ATQ ³	-55°C to +125°C	Q-18
ADG528ATE ³	-55°C to +125°C	E-20A
ADG529AKN	-40°C to +85°C	N-18
ADG529AKP	-40°C to +85°C	P-20A
ADG529ABQ	-40°C to +85°C	Q-18
ADG529ATQ ³	-55°C to +125°C	Q-18
ADG529ATE ³	-55°C to +125°C	E-20A

NOTES

¹To order MIL-STD-883, Class B processed parts, add /883B to part number. See Analog Devices Military Products Databook (1990) for military data sheet.

²E = Leadless Ceramic Chip Carrier (LCCC); N = Plastic DIP; P = Plastic Leaded Chip Carrier (PLCC); Q = Cerdip.

REV. A

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ADG528A/ADG529A—SPECIFICATIONS

Dual Supply ($V_{DD} = +10.8V$ to $+16.5V$, $V_{SS} = -10.8V$ to $-16.5V$ unless otherwise noted.)

Parameter	ADG528A ADG529A K Version		ADG528A ADG529A B Version		ADG528A ADG529A T Version		Units	Comments
	-40°C to +25°C +85°C		-40°C to +25°C +85°C		-55°C to +25°C +125°C			
ANALOG SWITCH								
Analog Signal Range	V_{SS} V_{DD}	V_{SS} V_{DD}	V_{SS} V_{DD}	V_{SS} V_{DD}	V_{SS} V_{DD}	V_{SS} V_{DD}	V min V max	
R_{ON}	280 450 300	600 400	280 450 300	600 400	280 450 300	400 600	Ω typ Ω max Ω max	-10V \leq V_S \leq +10V, $I_{DS} = 1mA$; Test Circuit 1 $V_{DD} = 15V(\pm 10\%)$, $V_{SS} = -15V(\pm 10\%)$ $V_{DD} = 15V(\pm 5\%)$, $V_{SS} = -15V(\pm 5\%)$ -10V \leq V_S \leq +10V, $I_{DS} = 1mA$ -10V \leq V_S \leq +10V, $I_{DS} = 1mA$
R_{ON} Drift	0.6		0.6		0.6		%/°C typ	
R_{ON} Match	5		5		5		% typ	
I_S (OFF), Off Input Leakage	0.02 1	50	0.02 1	50	0.02 1	50	nA typ nA max	$V_1 = \pm 10V$, $V_2 = \mp 10V$; Test Circuit 2
I_D (OFF), Off Output Leakage	0.04		0.04		0.04		nA typ	$V_1 = \pm 10V$, $V_2 = \mp 10V$; Test Circuit 3
ADG528A	1	100	1	100	1	100	nA max	
ADG529A	1	50	1	50	1	50	nA max	
I_D (ON), On Channel Leakage	0.04		0.04		0.04		nA typ	$V_1 = \pm 10V$, $V_2 = \mp 10V$; Test Circuit 4
ADG528A	1	100	1	100	1	100	nA max	
ADG529A	1	50	1	50	1	50	nA max	
I_{DIFF} , Differential Off Output Leakage (ADG529A only)		25		25		25	nA max	$V_1 = \pm 10V$, $V_2 = \mp 10V$; Test Circuit 5
DIGITAL CONTROL								
V_{INH} , Input High Voltage		2.4		2.4		2.4	V min	
V_{INL} , Input Low Voltage		0.8		0.8		0.8	V max	
I_{INL} or I_{INH}		1		1		1	μA max	$V_{IN} = 0$ to V_{DD}
C_{IN} Digital Input Capacitance	8		8		8		pF max	
DYNAMIC CHARACTERISTICS¹								
$t_{TRANSITION}$	200 300	400	200 300	400	200 300	400	ns typ ns max	$V_1 = \pm 10V$, $V_2 = \mp 10V$; Test Circuit 6
t_{OPEN}	50 25	10	50 25	10	50 25	10	ns typ ns min	Test Circuit 7
$t_{ON}(EN, \overline{WR})$	200 300	400	200 300	400	200 300	400	ns typ ns max	Test Circuits 8 and 9
$t_{OFF}(EN, \overline{RS})$	200 300	400	200 300	400	200 300	400	ns typ ns max	Test Circuits 8 and 10
t_W Write Pulse Width	100	120	100	120	100	130	ns min	See Figure 1
t_S Address, Enable Setup Time		100		100		100	ns min	See Figure 1
t_H Address, Enable Hold Time		10		10		10	ns min	See Figure 1
t_{RS} Reset Pulse Width		100		100		100	ns min	See Figure 2
OFF Isolation	68 50		68 50		68 50		dB typ dB min	$V_{EN} = 0.8V$, $R_L = 1k\Omega$, $C_L = 15pF$, $V_S = 7V$ rms, $f = 100kHz$
C_S (OFF)	5		5		5		pF typ	$V_{EN} = 0.8V$
C_D (OFF)								
ADG528A	22		22		22		pF typ	$V_{EN} = 0.8V$
ADG529A	11		11		11		pF typ	
Q_{INJ} , Charge Injection	4		4		4		pC typ	$R_S = 0\Omega$, $V_S = 0V$; Test Circuit 11
POWER SUPPLY								
I_{DD}	0.6	1.5	0.6	1.5	0.6	1.5	mA typ mA max	$V_{IN} = V_{INL}$ or V_{INH}
I_{SS}	20	0.2	20	0.2	20	0.2	μA typ mA max	$V_{IN} = V_{INL}$ or V_{INH}
Power Dissipation	10	28	10	28	10	28	mW typ mW max	

NOTE

¹Sample tested at +25°C to ensure compliance.
Specifications subject to change without notice.

Single Supply ($V_{DD} = +10.8V$ to $+16.5V$, $V_{SS} = GND = 0V$ unless otherwise noted.)

Parameter	ADG528A ADG529A K Version		ADG528A ADG529A B Version		ADG528A ADG529A T Version		Units	Comments
	-40°C to +25°C +85°C		-40°C to +25°C +85°C		-55°C to +25°C +125°C			
ANALOG SWITCH								
Analog Signal Range	GND	GND	GND	GND	GND	GND	V min V max	
R_{ON}	V_{DD}	V_{DD}	V_{DD}	V_{DD}	V_{DD}	V_{DD}	Ω typ	$GND \leq V_S \leq +10V$, $I_{DS} = 0.5mA$; Test Circuit 1
R_{ON} Drift	500	1000	500	1000	500	1000	Ω max	
R_{ON} Match	0.6		0.6		0.6		%/°C typ	$GND \leq V_S \leq +10V$, $I_{DS} = 0.5mA$
I_S (OFF), Off Input Leakage	5		5		5		% typ	$GND \leq V_S \leq +10V$, $I_{DS} = 0.5mA$
I_D (OFF), Off Output Leakage	0.02		0.02		0.02		nA typ	$V_1 = +10V/GND$, $V_2 = GND/+10V$
ADG528A	1	50	1	50	1	50	nA max	Test Circuit 2
ADG529A	0.04		0.04		0.04		nA typ	$V_1 = +10V/GND$, $V_2 = GND/+10V$
ADG528A	1	100	1	100	1	100	nA max	Test Circuit 3
ADG529A	1	50	1	50	1	50	nA max	
I_D (ON), On Channel Leakage	0.04		0.04		0.04		nA typ	$V_1 = +10V/GND$, $V_2 = GND/+10V$
ADG528A	1	100	1	100	1	100	nA max	Test Circuit 4
ADG529A	1	50	1	50	1	50	nA max	
I_{DIFF} , Differential Off Output Leakage (ADG529A only)		25		25		25	nA max	$V_1 = +10V/GND$, $V_2 = GND/+10V$
								Test Circuit 5.
DIGITAL CONTROL								
V_{INH} , Input High Voltage		2.4		2.4		2.4	V min	
V_{INL} , Input Low Voltage		0.8		0.8		0.8	V max	
I_{INL} or I_{INH}		1		1		1	μA max	$V_{IN} = 0$ to V_{DD}
C_{IN} Digital Input Capacitance	8		8		8		pF max	
DYNAMIC CHARACTERISTICS¹								
$t_{TRANSITION}$	300		300		300		ns typ	$V_1 = +10V/GND$, $V_2 = GND/+10V$; Test Circuit 6
	450	600	450	600	450	600	ns max	
t_{OPEN}	50		50		50		ns typ	Test Circuit 7
	25	10	25	10	25	10	ns min	
$t_{ON}(EN, \overline{WR})$	250		250		250		ns typ	Test Circuits 8 and 9
	450	600	450	600	450	600	ns max	
$t_{OFF}(EN, \overline{RS})$	250		250		250		ns typ	Test Circuits 8 and 10
	450	600	450	600	450	600	ns max	
t_W Write Pulse Width	100	120	100	120	100	130	ns min	See Figure 1
t_S Address, Enable Setup Time		100		100		100	ns min	See Figure 1
t_H Address, Enable Hold Time		10		10		10	ns min	See Figure 1
t_{RS} Reset Pulse Width		100		100		100	ns min	See Figure 2
OFF Isolation	68		68		68		dB typ	$V_{EN} = 0.8V$, $R_L = 1k\Omega$, $C_L = 15pF$,
	50		50		50		dB min	$V_S = 3.5V$ rms, $f = 100kHz$
C_S (OFF)	5		5		5		pF typ	$V_{EN} = 0.8V$
C_D (OFF)								
ADG528A	22		22		22		pF typ	$V_{EN} = 0.8V$
ADG529A	11		11		11		pF typ	
Q_{INJ} , Charge Injection	4		4		4		pC typ	$R_S = 0\Omega$, $V_S = 0V$; Test Circuit 11
POWER SUPPLY								
I_{DD}	0.6		0.6		0.6		mA typ	$V_{IN} = V_{INL}$ or V_{INH}
		1.5		1.5		1.5	mA max	
Power Dissipation	11		11		11		mW typ	
		25		25		25	mW max	

NOTE

¹Sample tested at +25°C to ensure compliance.
Specifications subject to change without notice.

ADG528A/ADG529A

ABSOLUTE MAXIMUM RATINGS*

(T_A = +25°C unless otherwise noted)

V _{DD} to V _{SS}	44V
V _{DD} to GND	25V
V _{SS} to GND	-25V
Analog Inputs ¹	
Voltage at S, D	V _{SS} - 2V to V _{DD} + 2V or 20mA, Whichever Occurs First
Continuous Current, S or D	20mA
Pulsed Current S or D	
1ms Duration, 10% Duty Cycle	40mA

Digital Inputs¹

Voltage at A, EN, \overline{WR} , \overline{RS}	V _{SS} - 4V to V _{DD} + 4V or 20mA, Whichever Occurs First
Power Dissipation (Any Package)	
Up to +75°C	470mW
Derates above +75°C by	6mW/°C
Operating Temperature	
Commercial (K Version)	-40°C to +85°C
Industrial (B Version)	-40°C to +85°C
Extended (T Version)	-55°C to +125°C
Storage Temperature Range	-65°C to +150°C
Lead Temperature (Soldering, 10sec)	+300°C

NOTE

¹Overvoltage at A, EN, \overline{WR} , \overline{RS} , S or D will be clamped by diodes. Current should be limited to the maximum rating above.

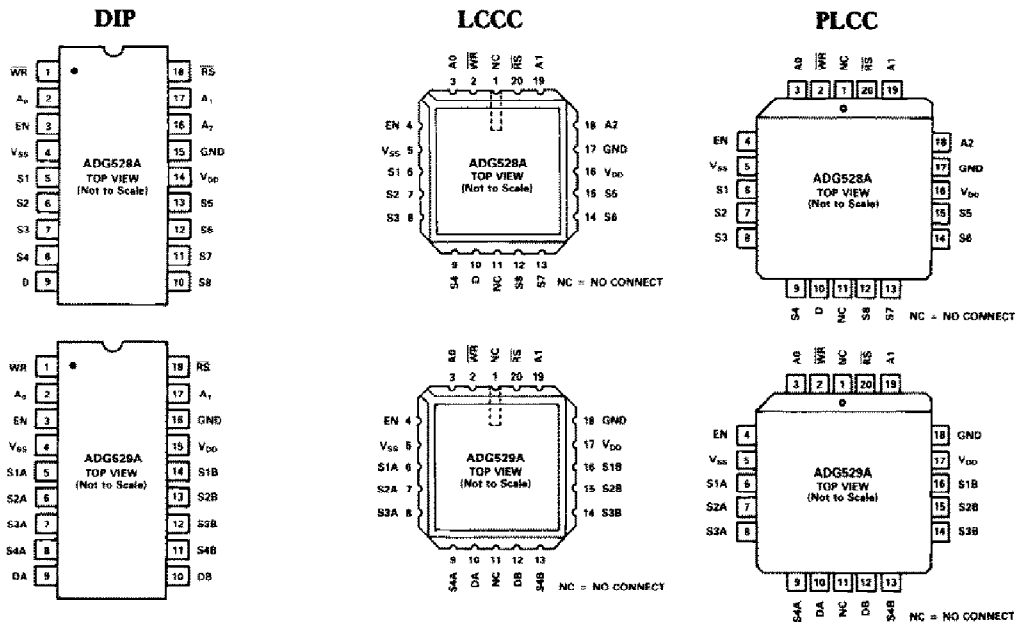
*COMMENT: Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

CAUTION

ESD (electrostatic discharge) sensitive device. The digital control inputs are diode protected; however, permanent damage may occur on unconnected devices subject to high energy electrostatic fields. Unused devices must be stored in conductive foam or shunts. The protective foam should be discharged to the destination socket before devices are removed.



PIN CONFIGURATIONS



TRUTH TABLES

A ₂	A ₁	A ₀	EN	\overline{WR}	\overline{RS}	ON SWITCH PAIR
X	X	X	X	\overline{f}	1	Retains Previous Switch Condition
X	X	X	X	X	0	NONE (Address and Enable Latches Cleared)
X	X	X	0	0	1	NONE
0	0	0	1	0	1	1
0	0	1	1	0	1	2
0	1	0	1	0	1	3
0	1	1	1	0	1	4
1	0	0	1	0	1	5
1	0	1	1	0	1	6
1	1	0	1	0	1	7
1	1	1	1	0	1	8

X = Don't Care **ADG528A**

A ₁	A ₀	EN	\overline{WR}	\overline{RS}	ON SWITCH PAIR
X	X	X	\overline{f}	1	Retains Previous Switch Condition
X	X	X	X	0	NONE (Address and Enable Latches Cleared)
X	X	0	0	1	NONE
0	0	1	0	1	1
0	1	1	0	1	2
1	0	1	0	1	3
1	1	1	0	1	4

X = Don't Care **ADG529A**

TIMING DIAGRAMS

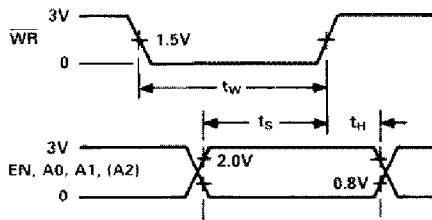


Figure 1

Figure 1 shows the timing sequence for latching the switch address and enable inputs. The latches are level sensitive; therefore, while \overline{WR} is held low, the latches are transparent and the switches respond to the address and enable inputs. This input data is latched on the rising edge of \overline{WR} .

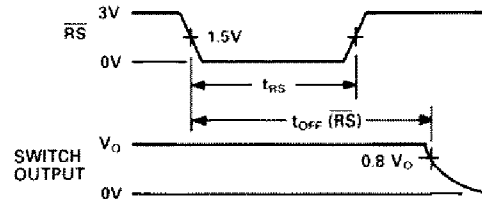


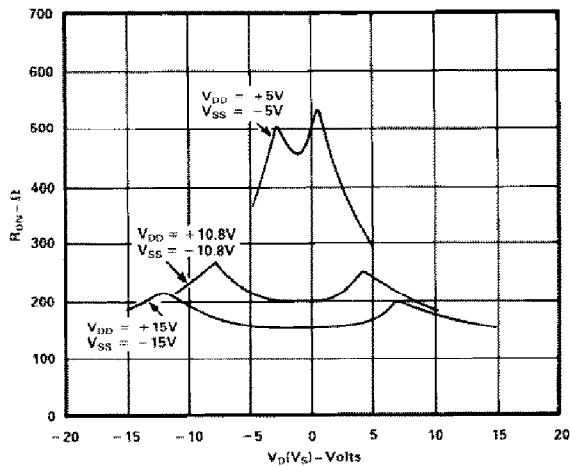
Figure 2

Figure 2 shows the Reset Pulse Width, t_{RS} , and Reset Turn-off Time, $t_{OFF} (RS)$.

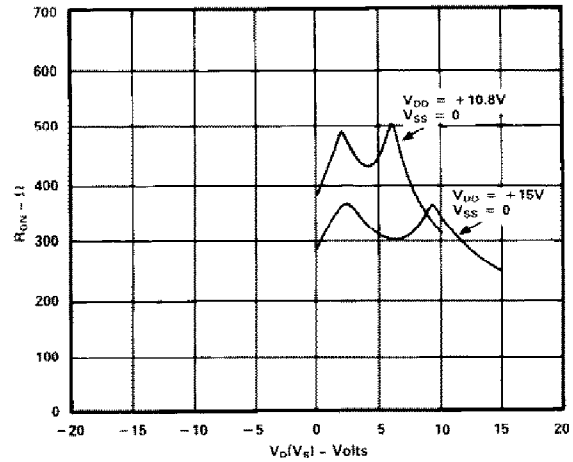
Note: All digital input signals rise and fall times measured from 10% to 90% of 3V. $t_R = t_F = 20ns$.

Typical Performance Characteristics

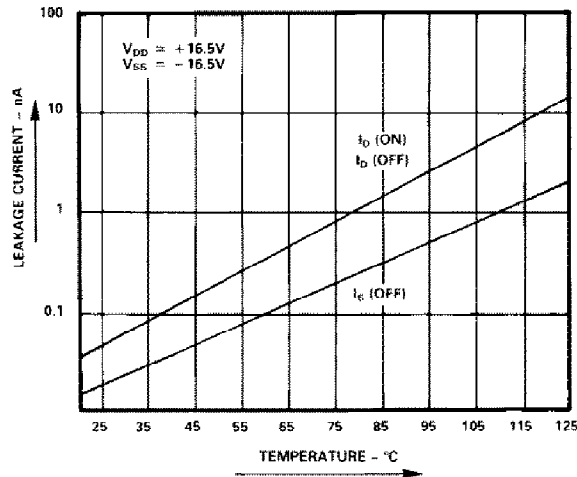
The multiplexers are guaranteed functional with reduced single or dual supplies down to 4.5V.



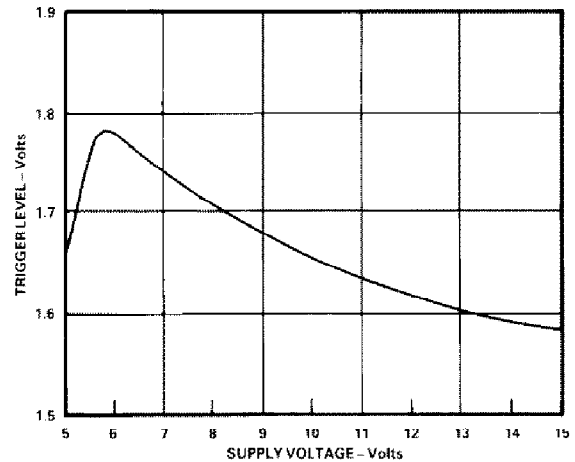
R_{ON} as a Function of $V_D(V_S)$: Dual Supply Voltage, $T_A = +25^\circ C$



R_{ON} as a Function of $V_D(V_S)$: Single Supply Voltage, $T_A = +25^\circ C$

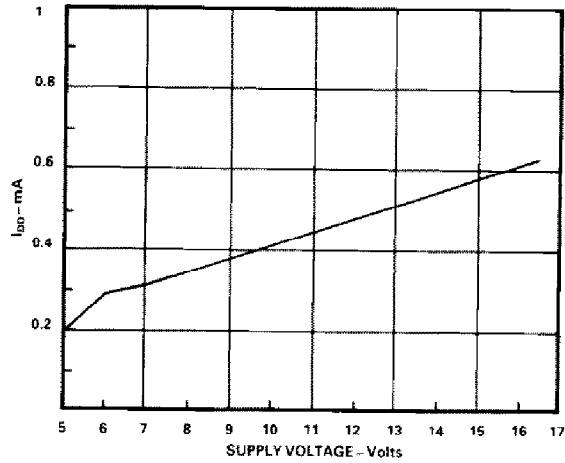
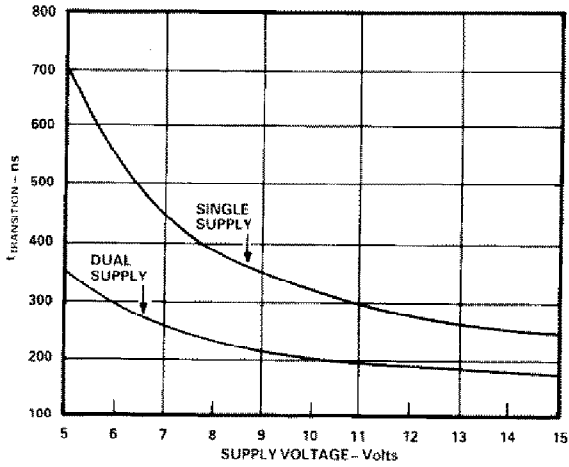


Leakage Current as a Function of Temperature (Note: Leakage Currents Reduce as the Supply Voltages Reduce)



Trigger Levels vs. Power Supply Voltage, Dual or Single Supply, $T_A = +25^\circ C$

ADG528A/ADG529A

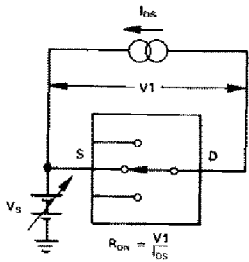


$t_{\text{TRANSITION}}$ vs. Supply Voltage: Dual and Single Supplies, $T_A = +25^\circ\text{C}$
 (Note: For V_{DD} and $|V_{\text{SS}}| < 10\text{V}$; $V_1 = V_{\text{DD}}/V_{\text{SS}}$, $V_2 = V_{\text{SS}}/V_{\text{DD}}$. See Test Circuit 6)

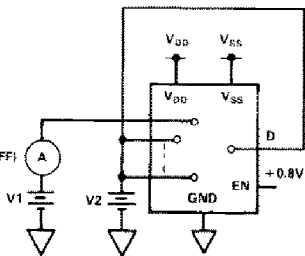
I_{DD} vs. Supply Voltage: Dual or Single Supply, $T_A = +25^\circ\text{C}$

Test Circuits

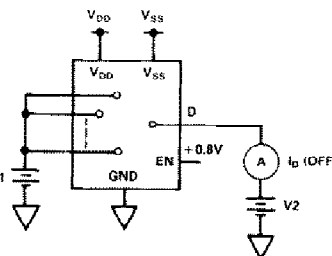
TEST CIRCUIT 1
 R_{ON}



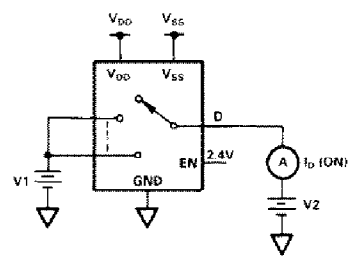
TEST CIRCUIT 2
 I_{S} (OFF)



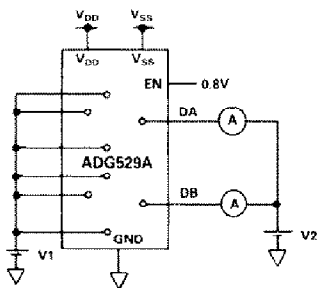
TEST CIRCUIT 3
 I_{D} (OFF)



TEST CIRCUIT 4
 I_{D} (ON)

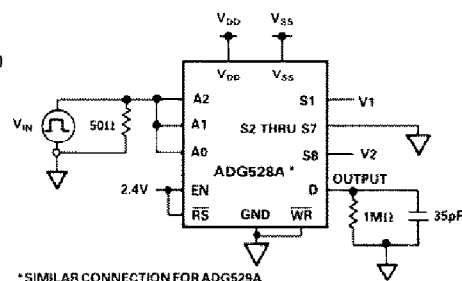
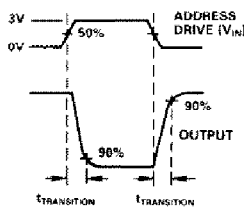


TEST CIRCUIT 5
 I_{DIFF}



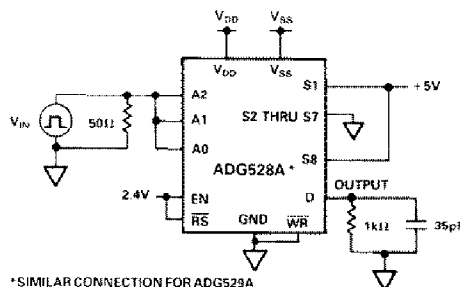
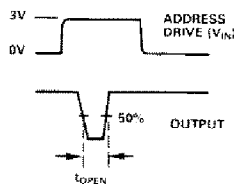
$$I_{\text{DIFF}} = I_{\text{DA}}(\text{OFF}) - I_{\text{DB}}(\text{OFF})$$

TEST CIRCUIT 6
SWITCHING TIME OF MULTIPLEXER, $t_{\text{TRANSITION}}$



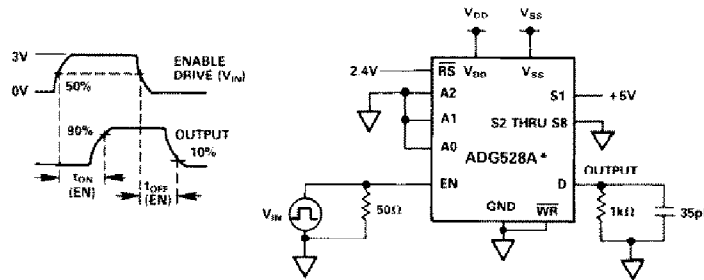
*SIMILAR CONNECTION FOR ADG529A

TEST CIRCUIT 7
BREAK-BEFORE-MAKE DELAY, t_{OPEN}



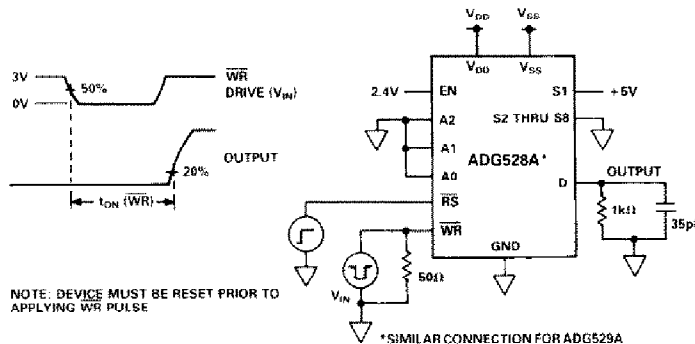
*SIMILAR CONNECTION FOR ADG529A

TEST CIRCUIT 8
ENABLE DELAY, $t_{ON}(EN)$, $t_{OFF}(EN)$



*SIMILAR CONNECTION FOR ADG529A

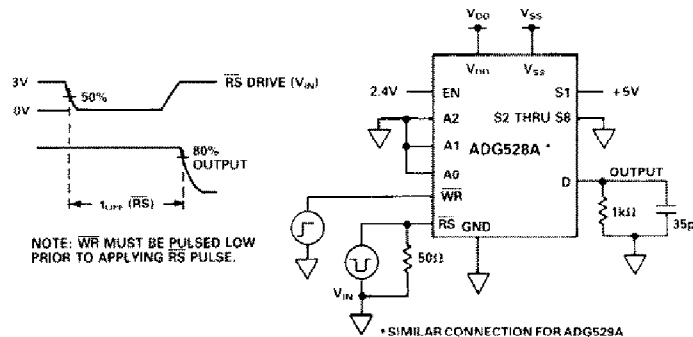
TEST CIRCUIT 9
WRITE TURN-ON TIME, $t_{ON}(WR)$



NOTE: DEVICE MUST BE RESET PRIOR TO APPLYING WR PULSE

*SIMILAR CONNECTION FOR ADG529A

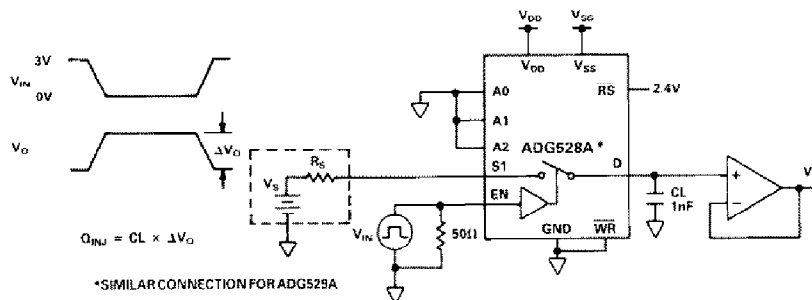
TEST CIRCUIT 10
RESET TURN-OFF TIME, $t_{OFF}(RS)$



NOTE: WR MUST BE PULSED LOW PRIOR TO APPLYING RS PULSE.

*SIMILAR CONNECTION FOR ADG529A

TEST CIRCUIT 11
CHARGE INJECTION



$Q_{INJ} = CL \times \Delta V_O$

*SIMILAR CONNECTION FOR ADG529A

ADG528A/ADG529A

TERMINOLOGY

R_{ON}	Ohmic resistance between terminals D and S	$t_{OFF} (EN)$	Delay time between the 50% and 10% points of the digital input and switch "OFF" condition
$R_{ON} \text{ Match}$	Difference between the R_{ON} of any two channels	$t_{TRANSITION}$	Delay time between the 50% and 90% points of the digital inputs and switch "ON" condition when switching from one address state to another
$R_{ON} \text{ Drift}$	Change in R_{ON} versus temperature		
$I_S (OFF)$	Source terminal leakage current when the switch is off	t_{OPEN}	"OFF" time measured between 50% points of both switches when switching from one address state to another
$I_D (OFF)$	Drain terminal leakage current when the switch is off	V_{INL}	Maximum input voltage for Logic "0"
$I_D (ON)$	Leakage current that flows from the closed switch into the body	V_{INH}	Minimum input voltage for Logic "1"
$V_S (V_D)$	Analog voltage on terminal S or D	$I_{INL} (I_{INH})$	Input current of the digital input
$C_S (OFF)$	Channel input capacitance for "OFF" condition	V_{DD}	Most positive voltage supply
$C_D (OFF)$	Channel output capacitance for "OFF" condition	V_{SS}	Most negative voltage supply
C_{IN}	Digital input capacitance	I_{DD}	Positive supply current
$t_{ON} (EN)$	Delay time between the 50% and 90% points of the digital input and switch "ON" condition	I_{SS}	Negative supply current

MECHANICAL INFORMATION

OUTLINE DIMENSIONS

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